

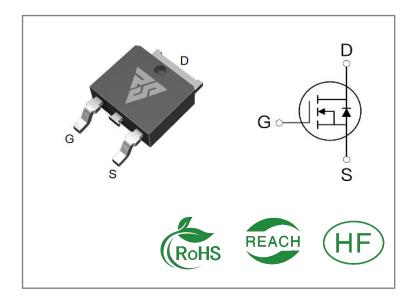
ID	R _{DS} (ON)(Typ)	VDSS
18A	0.12Ω	200V

Applications:

- Load Switch
- PWM Applications
- Power Managment

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



Ordering Information

Part Number	Package	Package Marking		Qty.	
RS640D	T0-252	RS640D	Tape&reel	2500 PCS	

Absolute Maximun Ratings Tc= 25℃ unless otherwise specified

Symbol	Parameter	RS640D	Units
VDSS	Drain-to-Source Voltage	200	V
ID	Continuous Drain Current TC=25℃	18	Α
IDM	Pulsed Drain Current	72	
PD	Power Dissipation	98	W
VGS	Gate- to- Source Voltage	±20	V
EAS	Single Pulse Avalanche Engergy L = 0.5mH,VDD = 30V, VG = 10V, Tj = 25℃	248	mJ
	Maximum Temperature for Soldering		
TL TPKG	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	300 260	$^{\circ}$
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

^{*} Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.



Thermal Resistance

Symbol	Parameter	RS640D	Units	Test Conditions
RθJC	Junction-to-Case	1.2	°C/W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 $^{\circ}{\rm C}$
RθJA	Junction-to- Ambient	60		1 cubic foot chamber,free air.

OFF Characteristics TJ= 25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	200			V	VGS=0V,ID=250μ A
IDSS	Drain- to- Source Leakage Current			1	μΑ	VDS=200V,VGS= 0V
ICCC	Gate- to- Source Forward Leakage			100	- A	VGS=20V ,VDS=0 V
IGSS	Gate- to- Source Reverse Leakage			-100	nA	VGS=-20V ,VDS= 0V

ON Characteristics TJ=25 °C unless otherwise specified

Symbol	Parameter		Тур.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On- Resistance		0.12	0.15	Ω	VGS=10V,ID=4.5 A
VGS(TH	Gate Threshold Voltage	2.0		4.0	V	VGS=VDS,ID=25 0μA

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter		Тур.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time		40			
trise	Rise Time		33			VDD=100V
td(OFF)	Turn- OFF Delay Time		166		nS	ID=18A RG=25Ω
tfall	Fall Time		60			



Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
Ciss	Input Capacitance		1200			VGS= 0V	
Coss	Output Capacitance		161		pF	VDS=25V	
Crss	Reverse Transfer Capacitance		70			f=1.0MHz	
Qg	Total Gate Charge		38			VDS= 160V	
Qgs	Gate- to- Source Charge		6		nC	ID=9A	
Qgd	Gate-to-Drain(" Miller") Charge		16			VGS=18V	

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
IS	Continuous Source Current			18	Α	Integral pn- diode
ISM	Maximum Pulsed Current			72	Α	in MOSFET
VSD	Diode Forward Voltage			1.4	V	IS=9A,VGS=0V
trr	Reverse Recovery Time		182		nS	VGS=0V
Qrr	Reverse Recovery Charge		1.29		μС	IS=18A di/dt=100A/μs

Notes:

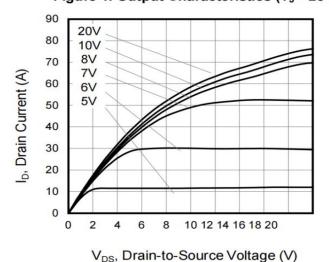
^{* 1.} Repetitive rating, pulse width limited by maximum junction temperature.

^{* 2.} Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%



Typical Feature Curve

Figure 1. Output Characteristics (T_J= 25°C)



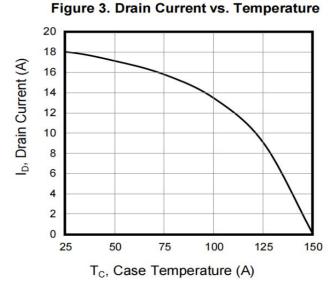
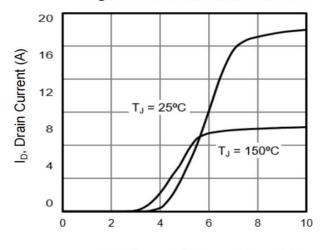


Figure 5. Transfer Characteristics



V_{GS}, Gate-to-Source Voltage (V)

Figure 2. Body Diode Forward Voltage

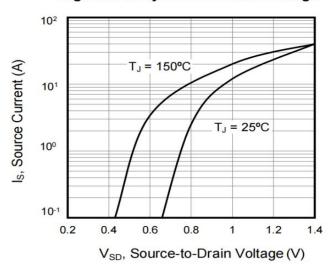


Figure 4. BV_{DSS} Variation vs. Temperature

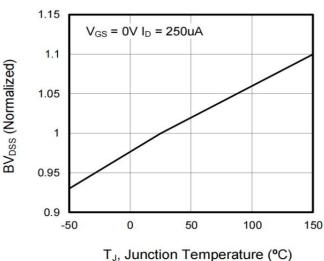
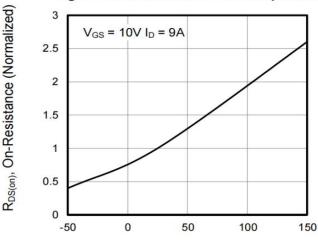


Figure 6. On-Resistance vs. Temperature



T_J, Junction Temperature (°C)



Figure 7. Capacitance 104 Capacitance (pF) Ciss 10³ Coss 10² $V_{GS} = 0V$ f = 1MHz 10¹ 10 0 20 30 40 V_{DS}, Drain-to-Source Voltage (V)

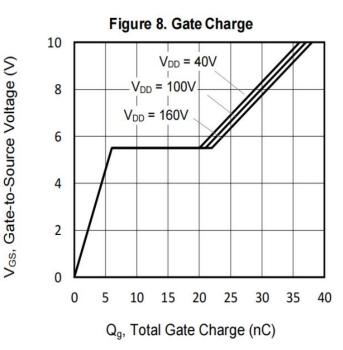
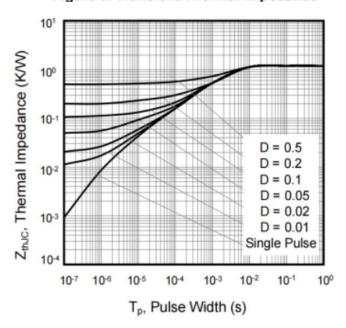


Figure 9. Transient Thermal Impedance





Test ircuits and Waveforms

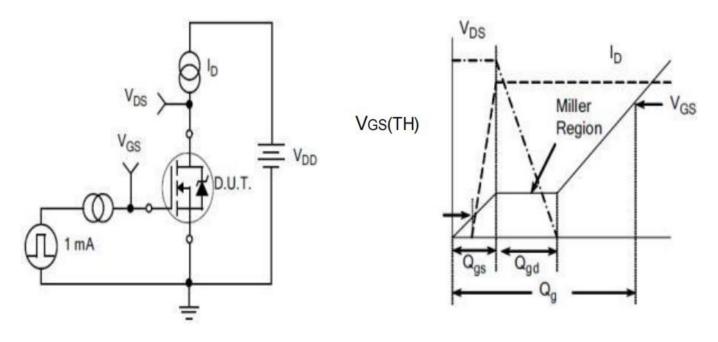


Figure A.
Gate Charge Test Circuit

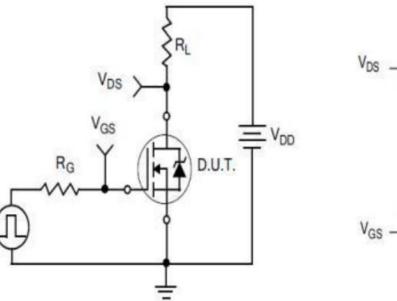


Figure C.
Resistive Switching Test Circuit

Figure B.
Gate Charge Waveform

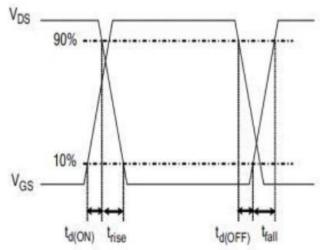
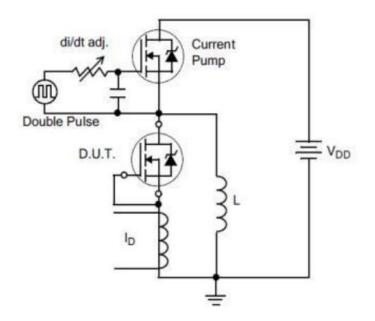


Figure D.
Resistive Switching Waveforms



Test ircuits and Waveforms



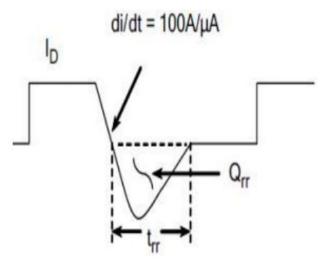


Figure E.Diode Reverse Recovery Test Circuit

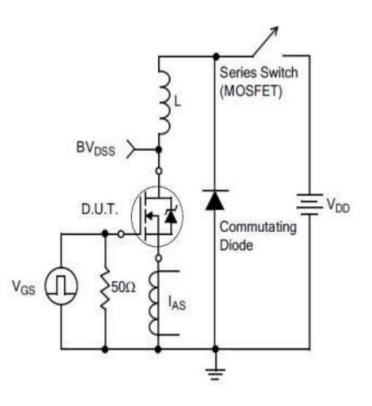


Figure F.Diode Reverse Recovery Waveform

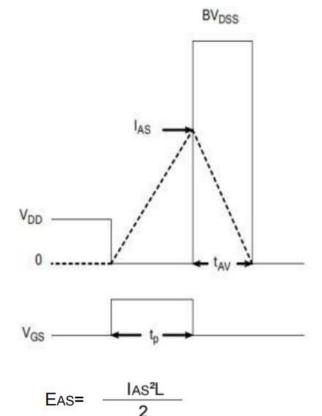
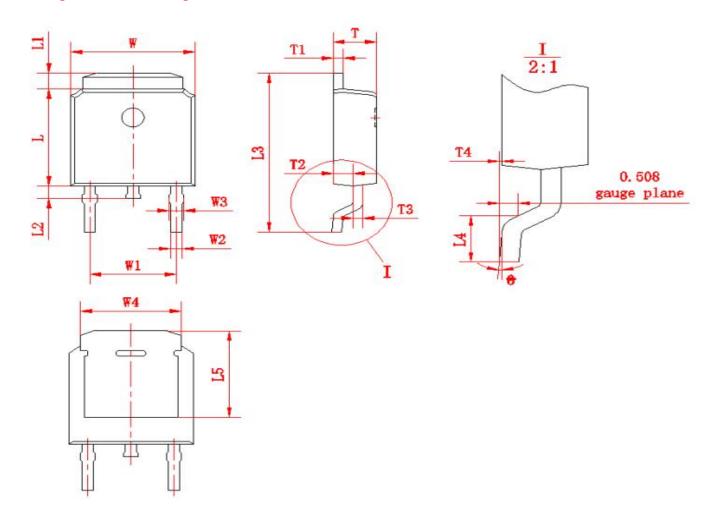


Figure G.Unclamped Inductive Switching Test Circuit

Figure H.Unclamped Inductive Switching Waveforms



Package outline drawing(TO-252 Unit: mm)



符号	尺	尺寸		尺寸		<i>/</i> // 口	尺寸	
14.2	Min	Max	符号	Min	Max	符号	Min	Max
W	6.50	6.70	L1	0.80	1.20	T1	0.48	0.58
W1	(4.5	(4.572)		0.60 1.00		T2	0.95	1.15
W2	0.6	0.8	L3	9.70	10.30	Т3	0.48	0.58
W3	0.68	0.88	L4	1.30	1.70	T4	0.00	0.12
W4	(5	.3)	L5	(5.20)		0	0	8
L	6.00	6.20	Т	2.20	2.40			



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